



FORM PTO/SB/08A/B (10-01)  
Substitute for PTO-1449A/B

**INFORMATION DISCLOSURE**

**STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Attorney Docket Number

45129/RAG/C766

Application Number

09/927,779

Filing Date

August 9, 2001

Applicant(s)

Michael L. Roukes, et al.

Group Art Unit

1641

Examiner Name

Ann Y. Lam

**U.S. PATENT DOCUMENTS**

EXAMINER INITIALS	Cite No. <sup>1</sup>	DOCUMENT NUMBER Number - Kind Code <sup>2</sup> (If Known)	PUBLICATION DATE MM-DD-YYYY	NAME OF PATENTEE
OP		5,282,924	02-01-1994	Bayer, et al.
OP		5,807,758	09-15-1998	Lee, et al.

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIALS	Cite No. <sup>1</sup>	Foreign Patent Document Country Code <sup>3</sup> - Number <sup>4</sup> - Kind Code <sup>5</sup> (If Known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	T <sup>6</sup> (✓)
OP		WO 98/50773	11-12-1998	Charych, et al.	
OP		WO 00/58729	10-05-2000	Thundat, et al.	
OP		WO 01/33226 A1	05-10-2001	Baller, et al.	

**OTHER DOCUMENTS**

EXAMINER INITIALS	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
OP		Supplemental European Search Report dated June 15, 2004, European Patent Application No. 01964587
OP		BASELT, David R., et al., "Biosensor based on force microscope technology", J. Vac. Sci. Technol. B 14(2), Mar/Apr 1996, pgs. 789-793; XP000613363
OP		LANG, H.P., et al., "An artificial nose based on a micromechanical cantilever array", Analytica Chimica Acta, Vol. 393, March 1999, pgs. 59-65; XP000990018
OP		FRITZ, J, et al., "Translating Biomolecular Recognition into Nanomechanics", Science, 14 April 2000, pgs. 316-319, Vol. 288; XP000971747

EXAMINER SIGNATURE		DATE CONSIDERED	2/3/05
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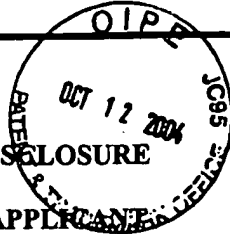
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*[Signature]*

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*[Signature]*

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*[Signature]*

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# INFORMATION DISCLOSURE

## STATEMENT BY APPLICANT

JUN 20 2003

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Attorney Docket Number	45129/JWP/C766
Application Number	09/927,779
Filing Date	August 9, 2001
Applicant(s)	Michael L. Roukes, et al.
Group Art Unit	2881 164
Examiner Name	Not Yet Determined LAM

## U.S. PATENT DOCUMENTS

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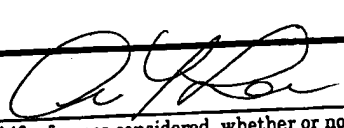
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## OTHER DOCUMENTS

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		PCT International Preliminary Examination Report dated April 22, 2003 from corresponding International Application No. PCT/US01/41645 filed August 9, 2001

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<p>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>See Kinds Codes of USPTO Patent Documents at www.pto.gov or MPEP 901.4. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup>Applicant is to place a check mark here if English Language Translation is attached.</p> <p>Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE</p>			

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Application Number 09/927,779

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Applicant(s) Michael L. Roukes, et al.

Group Art Unit 2881 1641

Examiner Name to be assigned LAM

U.S. PATENT DOCUMENTS

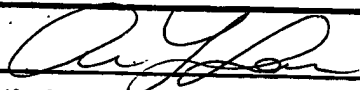
EXAMINER INITIALS	Cite No. <sup>1</sup>	DOCUMENT NUMBER Number - kind code <sup>2</sup> (If known)	PUBLICATION DATE MM-DD-YYYY	NAME OF PATENTEE
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AL		PCT International Search Report dated February 21, 2002 from corresponding PCT application No. PCT/US01/41645 filed August 9, 2001

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Application Number 09/927,779

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Applicant(s) Michael L. Roukes, et al.

Group Art Unit 2881/64

Examiner Name To be Assigned

## U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

## OTHER DOCUMENTS

EXAMINER INITIALS	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
CHUI	CHUI, B.W., et al., "Independent detection of vertical and lateral forces with a sidewall-implanted dual-axis piezoresistive cantilever", Appl. Phys. Lett., 16 March 1998, pgs. 1388-1390, Vol. 72, No. 11, American Institute of Physics.
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AL	MEINERS, Jens-Christian, et al., "Direct Measurement of Hydrodynamic Cross Correlations between Two Particles in an External Potential", Physical Review Letters, 8 March 1999, pgs. 2211-2214, Vol. 82, No. 10, The American Physical Society.
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